

INTERNATIONAL STANDARD

IEC 61337-1

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Filters using waveguide type dielectric resonators –

Part 1: Generic specification

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

FILTERS USING WAVEGUIDE TYPE DIELECTRIC RESONATORS –

Part 1: Generic specification

FOREWORD

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International Standard IEC 61337-1 has been prepared by IEC technical committee 49: Piezoelectric and dielectric devices for frequency control and selection.

This part of IEC 61337 cancels and replaces IEC 61337-1-1:1995 and IEC 61337-1-2:1999.

The text of this standard is based on the following documents:

FDIS	Report on voting
49/685/FDIS	49/695/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

IEC 61337 consists of the following parts, under the general title *Filters using waveguide type dielectric resonators*:

Part 1: Generic specification

Part 2: Guidance for use

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended.

A bilingual edition of this generic specification may be issued at a later date.

FILTERS USING WAVEGUIDE TYPE DIELECTRIC RESONATORS –

Part 1: Generic specification

1 General

1.1 Scope

This part of IEC 61337 applies to filters using waveguide type dielectric resonators of assessed quality using either capability approval or qualification approval procedures. It also lists the test and measurement procedures which may be selected for use in detail specifications for such filters.

1.2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60027 (all parts), *Letter symbols to be used in electrical technology*

IEC 60050(561):1991, *International Electrotechnical Vocabulary (IEV) – Chapter 561: Piezo-electric devices for frequency control and selection*

IEC 60068-1:1988, *Environmental testing – Part 1: General and guidance*

IEC 60068-2-1:1990, *Environmental testing – Part 2: Tests – Test A: Cold*

IEC 60068-2-2:1974, *Environmental testing – Part 2: Tests – Test B: Dry Heat*

IEC 60068-2-6:1995, *Environmental testing – Part 2: Tests – Test Fc: Vibration (sinusoidal)*

IEC 60068-2-7:1983, *Environmental testing – Part 2: Tests – Test Ga: Acceleration, steady state*

IEC 60068-2-13:1983, *Environmental testing – Part 2: Tests – Test M: Low air pressure*

IEC 60068-2-14:1984, *Environmental testing – Part 2: Tests – Test N: Change of temperature*

IEC 60068-2-20:1979, *Environmental testing – Part 2: Tests – Test T: Soldering*

IEC 60068-2-21:1999, *Environmental testing – Part 2-21: Tests – Test U: Robustness of terminations and integral mounting devices*

IEC 60068-2-27:1987, *Environmental testing – Part 2: Tests – Test Ea and guidance: Shock*

IEC 60068-2-29:1987, *Environmental testing – Part 2: Tests – Test Eb and guidance: Bump*

IEC 60068-2-30:1980, *Environmental testing – Part 2: Tests – Test Db and guidance: Damp heat, cyclic (12 + 12 hour cycle)*

IEC 60068-2-58:1999, *Environmental testing – Part 2-58: Tests – Tests Td: Test methods for solderability, resistance to dissolution of metalization and to soldering heat of surface mounting devices (SMD)*

IEC 60068-2-78:2001, *Environmental testing – Part 2-78: Tests – Test Cab: Damp heat, steady state*

IEC 60617 (all parts) [DB]¹, *Graphical symbols for diagrams*

QC 001001:2000, *IEC Quality Assessment System for Electronic Components (IECQ) – Basic Rules*

QC 001002-2:1998, *IEC Quality Assessment System for Electronic Components (IECQ) – Rules of Procedure – Part 2: Documentation*

QC 001002-3:1998, *IEC Quality Assessment System for Electronic Components (IECQ) – Rules of Procedure – Part 3: Approval Procedures*

QC 001005:2000, *Register of Firms, Products and Services approved under the IECQ System, including ISO 9000*

ISO 1000:1992, *SI units and recommendation for the use of their multiples and of certain other units*

¹ “DB” refers to the IEC on-line database.